L Number	Hits	Search Text	DB	Time stamp
-	502	714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/24 10:27
-	12	714/733.ccls. and ((instruction instructions) same (external adj (test tests tester)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/24 10:31
-	2	5982681.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/24 10:37
-	29	714/733.ccls. and ((test external) adj (instruction instructions))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/24 12:53
-	2355	714/718.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/24 12:55
-	5	714/718.ccls. and (initialization with (BIST built-in-self-test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/24 13:02
-	0	(5161232,5202978,5291425,5301199,5303199,5355509,5361264,5369648,5398250,544811... 0,5459737,5485467,55049C	USPAT; US-PGPUB; DERWENT	2002/10/30 16:04
-	0	(5161232,5202978,5291425,5301199,5303199,5355509,5361264,5369648,5398250,544811... 0,5459737,5485467,55049C	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/30 16:05
-	23	(5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264, 5369648, 5398250, 5448110, 5459737, 5485467, 5504903,5509019,555308,5619512,5640509,5668816,5802071).pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/30 16:05
-	40	(5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264, 5369648, 5398250, 5448110, 5459737, 5485467, 5504903, 5509019, 555308, 5619512, 5640509, 5668816, "5802071").pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/10/30 16:06
-	229	(5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619, 5771241, 5898703, 5396498, "4433413").pn	USPAT; US-PGPUB; DERWENT	2002/10/30 16:08
-	229	(5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619, 5771241, 5898703, 5396498, "4433413").pn	USPAT; US-PGPUB; DERWENT	2002/10/30 16:08
-	2	((5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264, 5369648, 5398250, 5448110, 5459737, 5485467, 5504903, 5509019, 555308, 5619512, 5640509, 5668816, "5802071").pn.) and ((5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619, 5771241, 5898703, 5396498, "4433413").pn)	USPAT; US-PGPUB; DERWENT	2002/10/30 16:10

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-	267	((5161232, 5202978, 5291425, 5301199, 5303199, 5355509, 5361264, 5369648, 5398250, 5448110, 5459737, 5485467, 5504903, 5509019, 555308, 5619512, 5640509, 5668816, "5802071").pn.) ((5961653, 5802071,6070252, 5119378, 6108798, 5675546, 5138619, 5771241, 5898703, 5396498, "4433413").pn)	USPAT; US-PGPUB; DERWENT	2002/10/30 16:09
-	2	5982681.pn.	USPAT; US-PGPUB; DERWENT	2002/10/31 16:47
-	2	5982681.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 16:40
-	420	((manufactur$3 and (board system circuit chip)) with test$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 16:10
-	39	(((manufactur$3 and (board system circuit chip)) with test$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 15:04
-	12288095	US 5539652.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 15:05
-	2	5539652.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 16:07
-	348	((manufactur$3 and (board system chip)) with test$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 16:14
-	4	(((manufactur$3 and (board system circuit chip)) with test$3) same (BIST self-test "self test" "built-in-self-test" "built in self test")).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 16:15
-	18	((manufactur$3 and (board system chip)) with test$3) same (BIST self-test "self test" "built-in-self-test" "built in self test").ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/24 16:17
-	305	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:02
-	5	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufacture and board) near (level test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:00
-	32	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:00

-	1	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:01
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/734.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:01
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/742.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:01
-	1	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/735.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:01
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/736.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:01
-	0	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/737.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:02
-	1	(((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM)) and ((manufactur$3 and board) near (level test))) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:02
-	1	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board)) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:02
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board)) and 714/734.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:02
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board)) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:03
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board)) and 714/742.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:03
-	0	((BIST "built in self test" "built-in-self-test" "built-in self-test") with (memory cache FLASH RAM ROM DRAM SRAM CAM) with (manufacture and board)) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/20 13:03

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